Sheet	1	of	1	

Form PTO-1449 US Dept. of Commerce (REV. 8-83) PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 117863			APPLICATION NO. New U.S. Patent Application						
INFORMATION DISCLOSURE STATEMENT							101	17214	161		
(Use several sheets if necessary)				APPLICANTS Eigo NAKAGAWA et al.							
				FILING DATE November 26, 2003			2829 .				
U.S. PATENT DOCUMENTS											
EXAMINER INITIAL	,	DOCUMENT NUMBER		DATE NAME		CLASS		SUB CLASS			
								-			
				··········							
					<u> </u>						
	L	FOREIG	N PA	ATENT DO	CUMENTS			······································			
		DOCUMENT NUMBER		DATE		COUNTRY		CLASS	SUB CLASS		
N	1	JP A 2000-74998 w/ abst & trans 03		14/2000	0 Japan						
Or	2	JP A 11-038111 w/ abst & trans 02		12/1999	Japan						
						•					
-											
		OTHER DOCUMENTS (Inc	ludin	g Author,	Title, Date, Pe	ertinent Pages, etc.)					
· ·	3	"Detection of Flaws in a Printed Circuit Board by Using an Eddy-Current Testing Approach" H. Fujiki et al; "http://www.magmacl.ec.t.kanazawa-u.ac.jp/magcap-j/research-j/ecta-j.html									
·											
	!										
· · · · · · · · · · · · · · · · · · ·											
											
i											
EXAMINER	L					DATE C	ONSIDI	ERED			
Jimm / Namer 10/14/05											
Examiner: Initial if citation considered, whether or hot citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.											

Date: November 26, 2003